

Balancing the Switching Losses of Paralleled SiC MOSFETs Using an Intelligent Gate Driver

Christoph Lüdecke

Institute for Power Electronics and Electrical Drives (ISEA)
RWTH Aachen University



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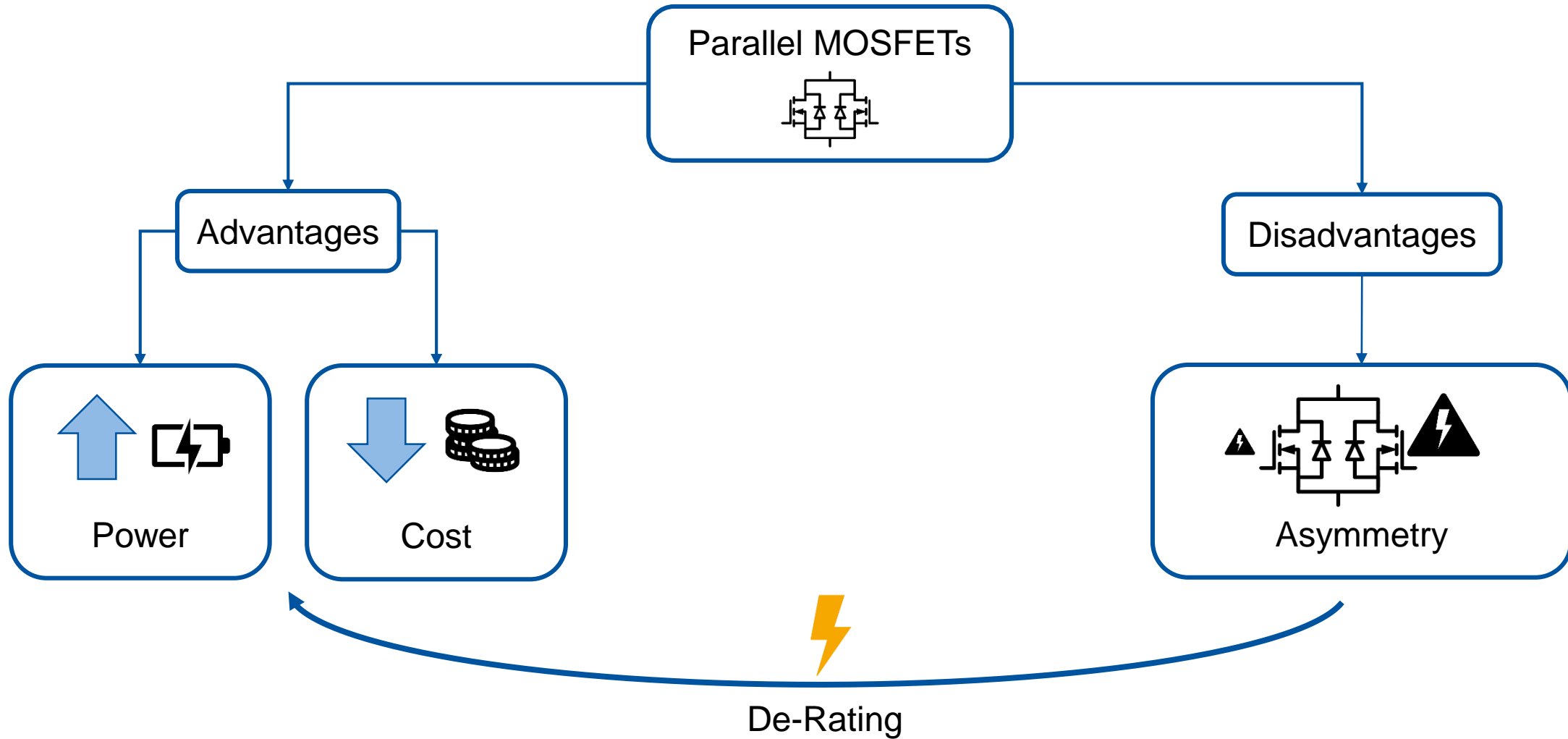


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Motivation



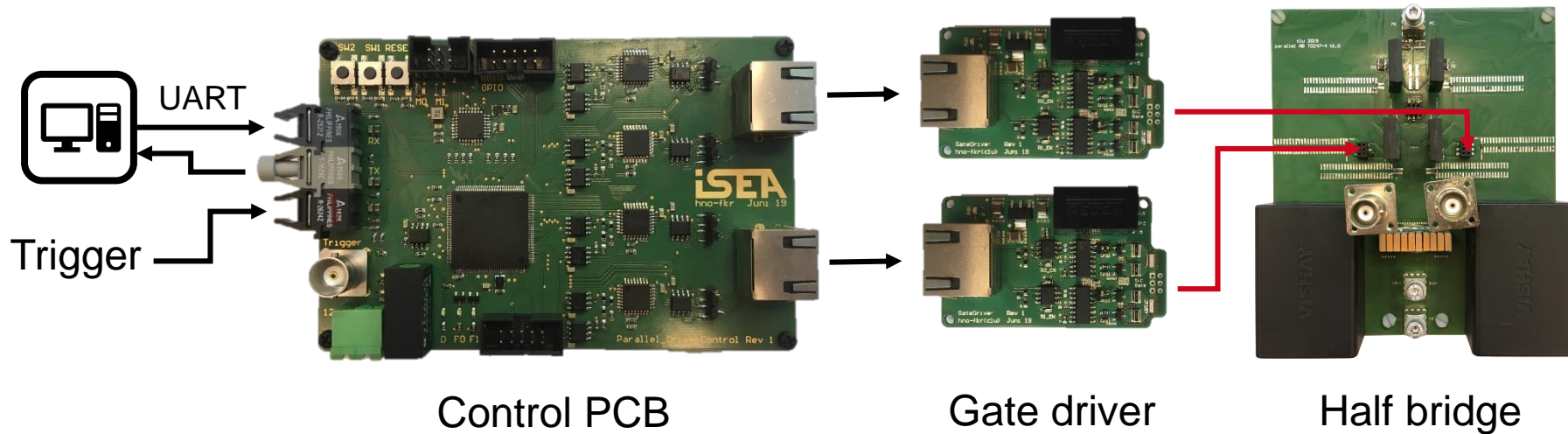
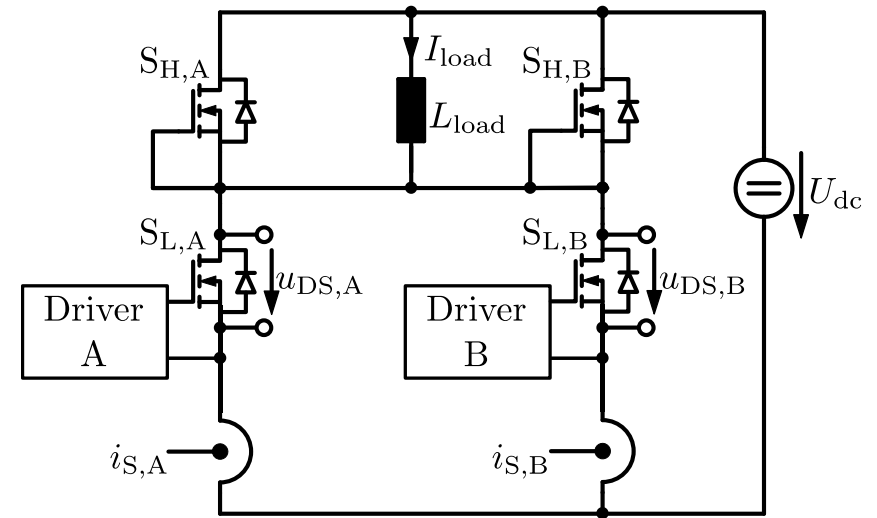
Content

- Motivation

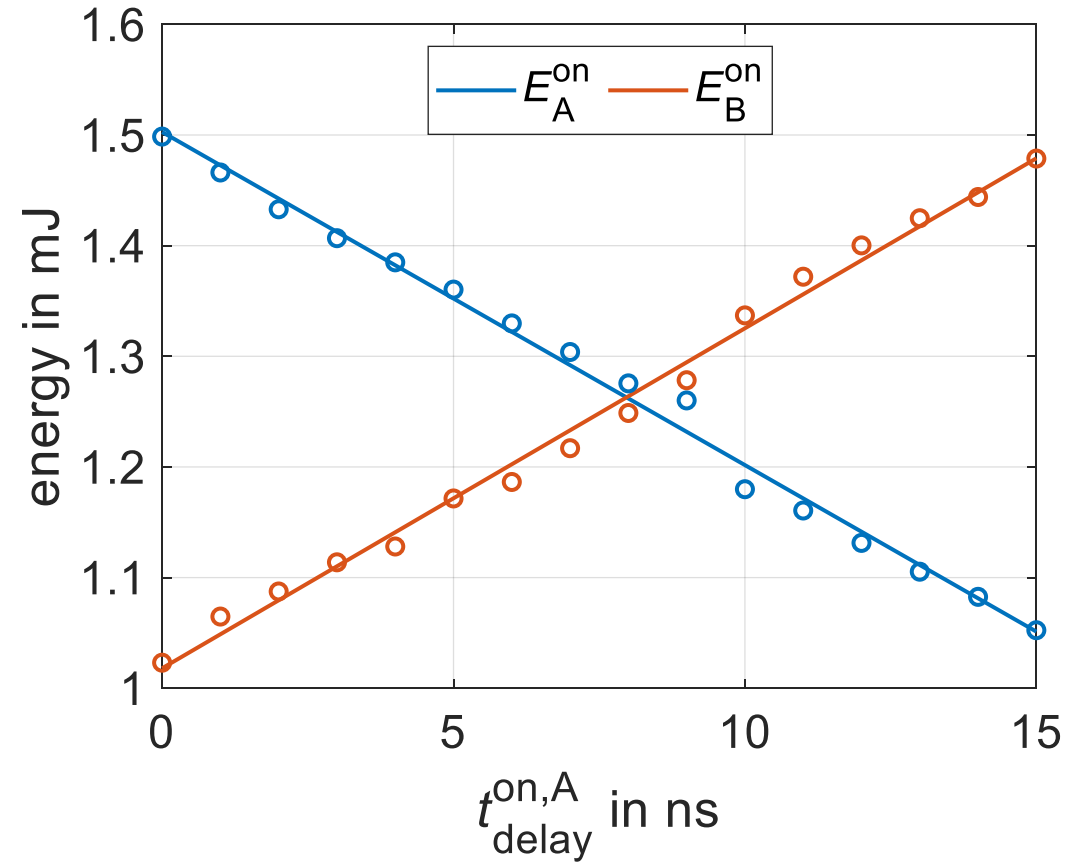
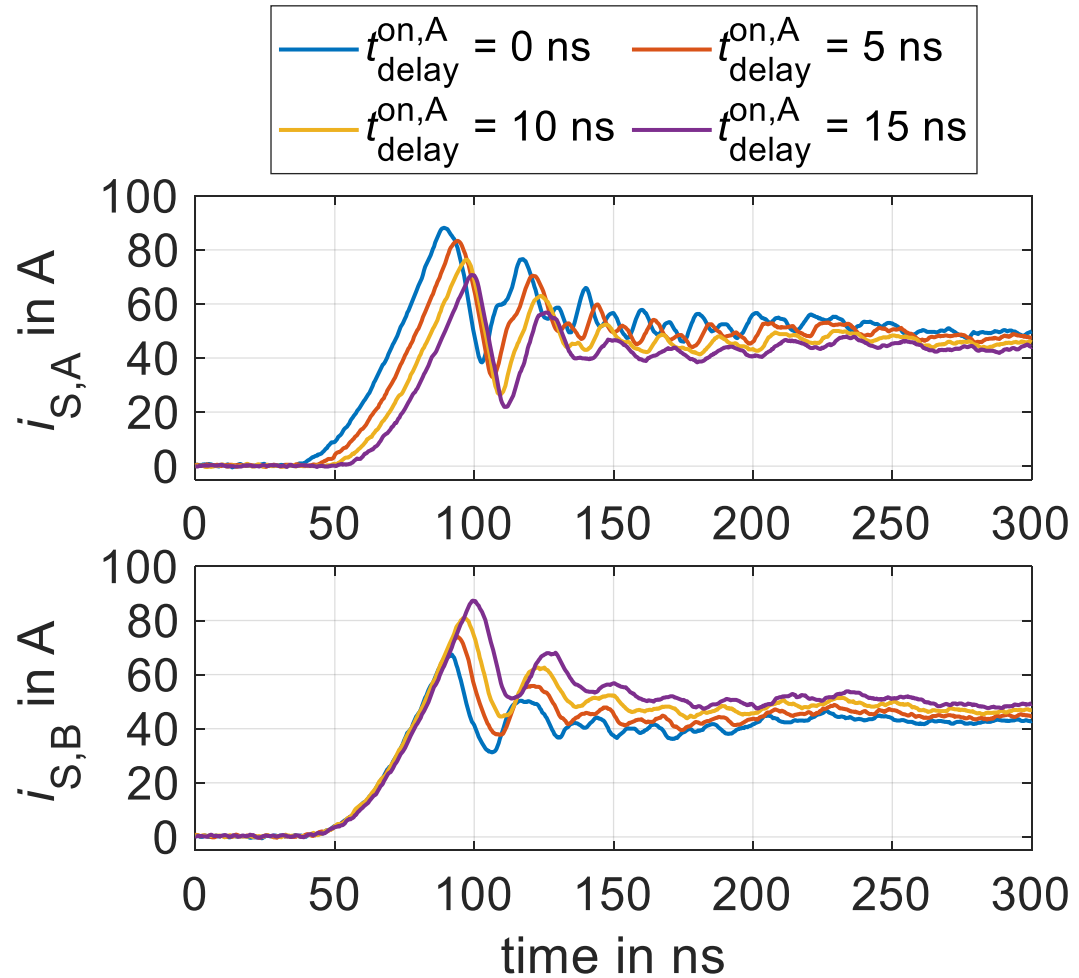
- Test Setup
- Influence of Gate Delay on Current Transients
 - Turn-on
 - Turn-off
- Conclusion & Outlook

Test Setup

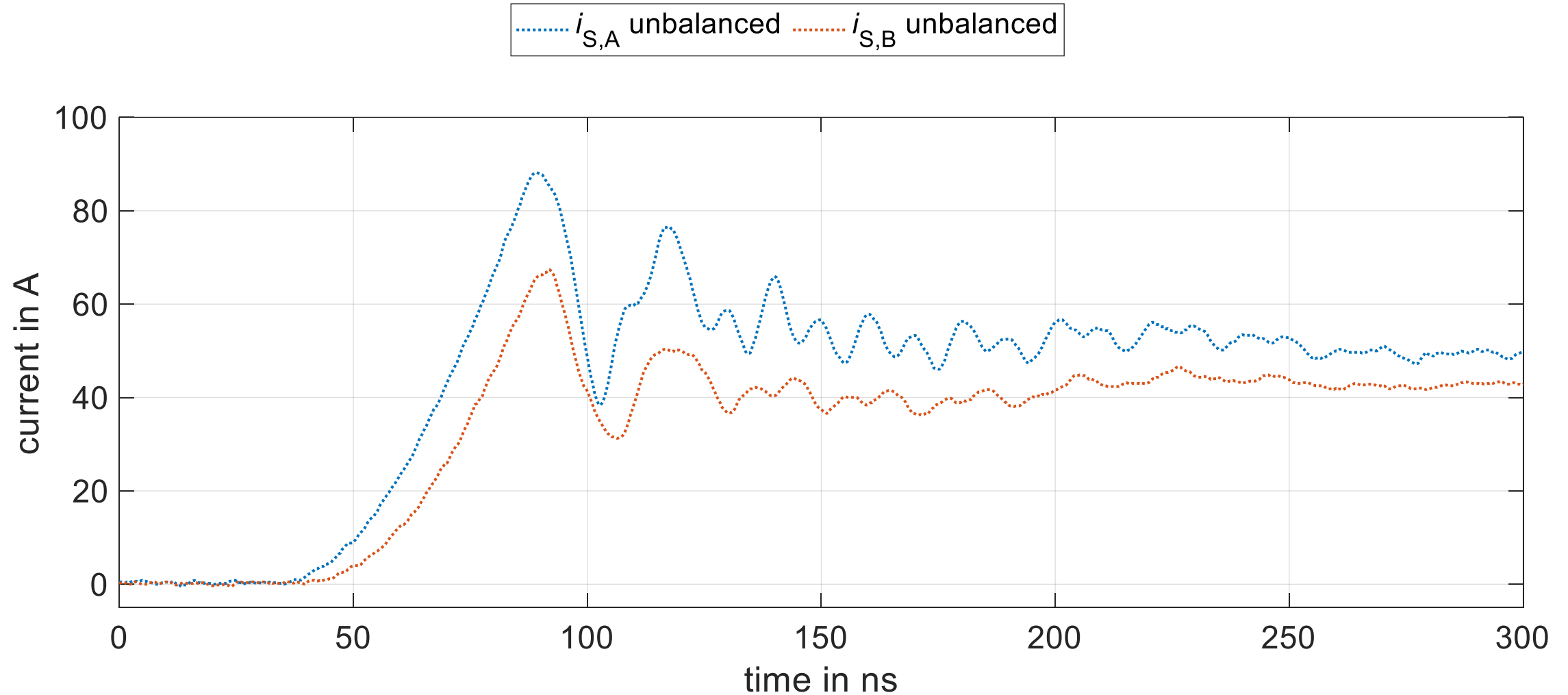
- Two parallel half bridges
 - 50 A, 1200 V per MOSFET
- Galvanically isolated gate driver for each low-side MOSFET
- FPGA controls gate signal delay
 - 0 ns ... 20 ns delay with 10 ps resolution



Influence of Gate Delay on Current Transients Turn-on

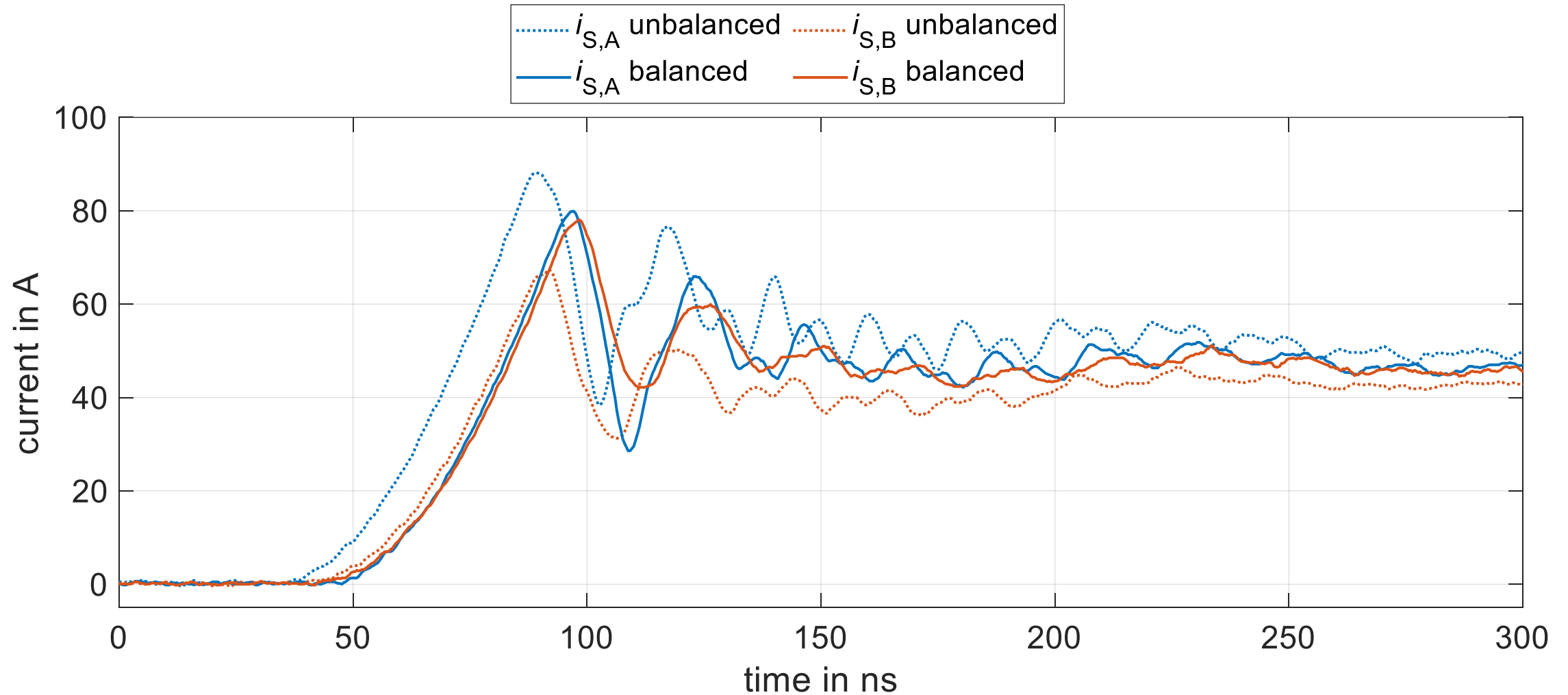


Influence of Gate Delay on Current Transients Turn-on

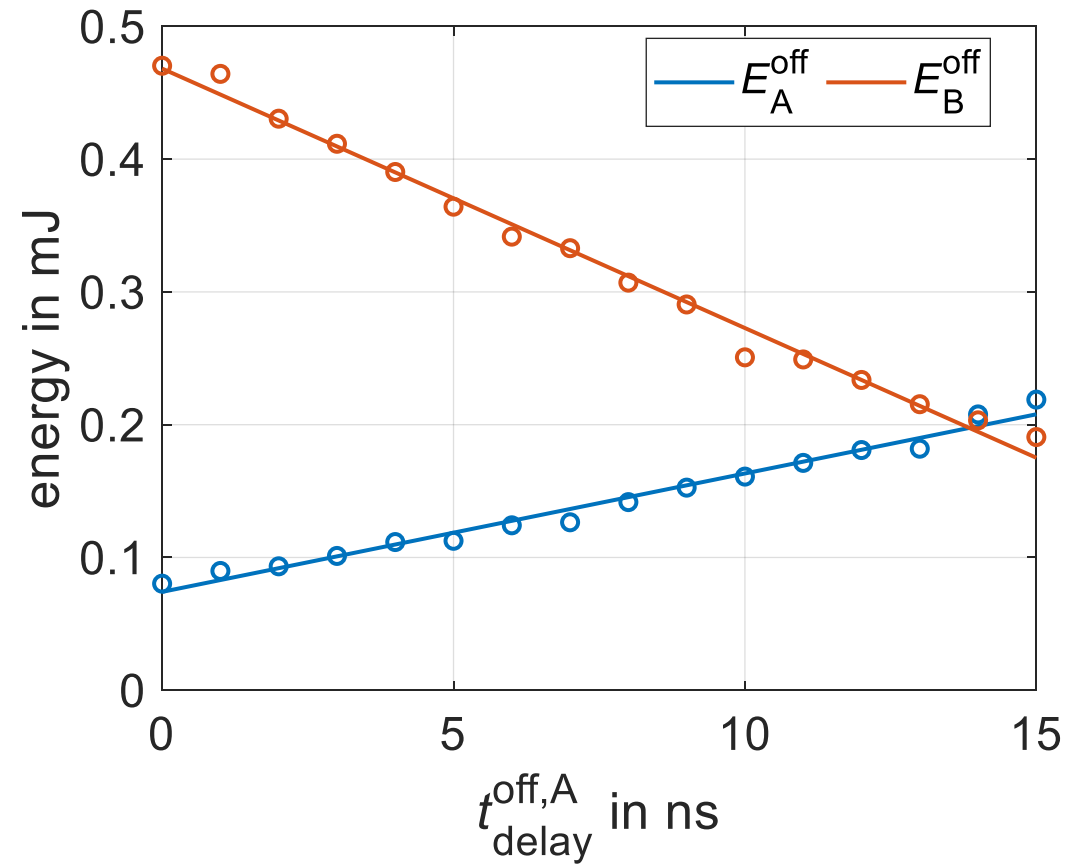
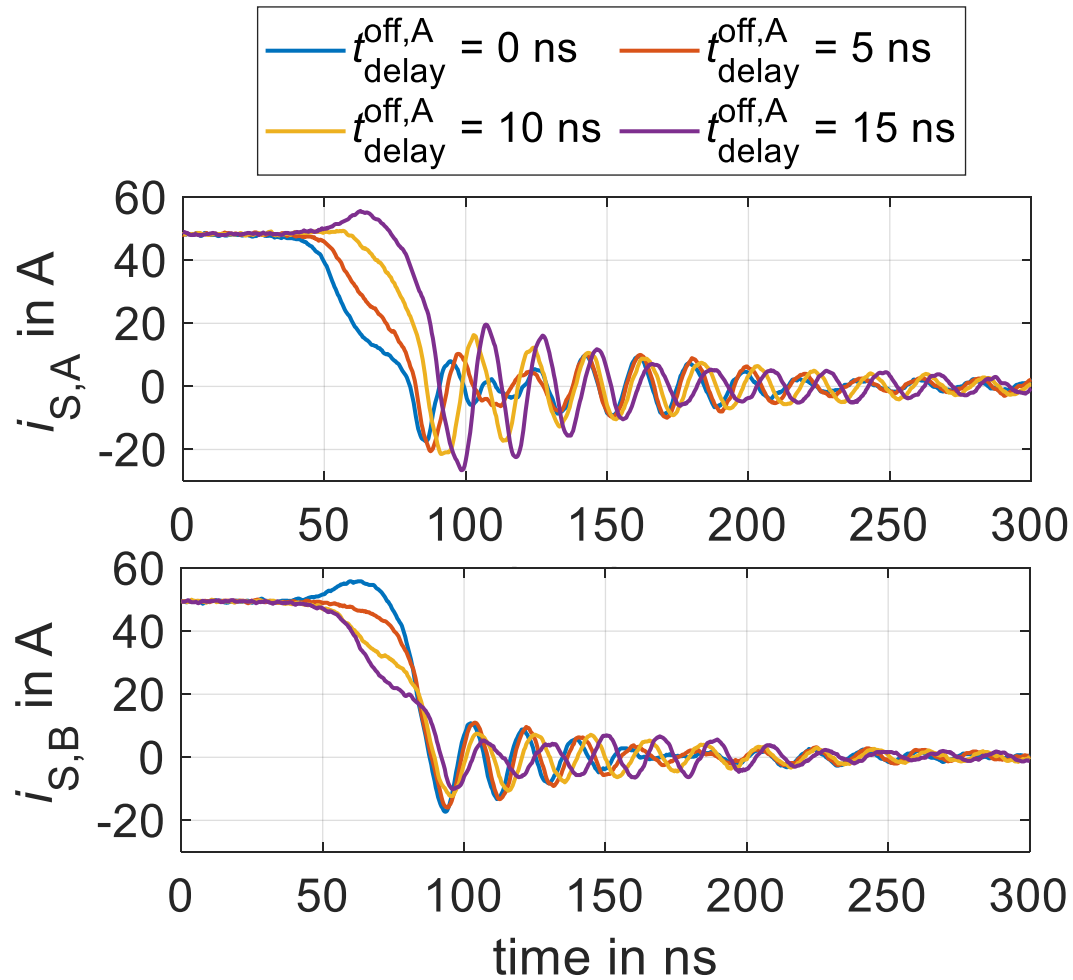


Influence of Gate Delay on Current Transients

Turn-on

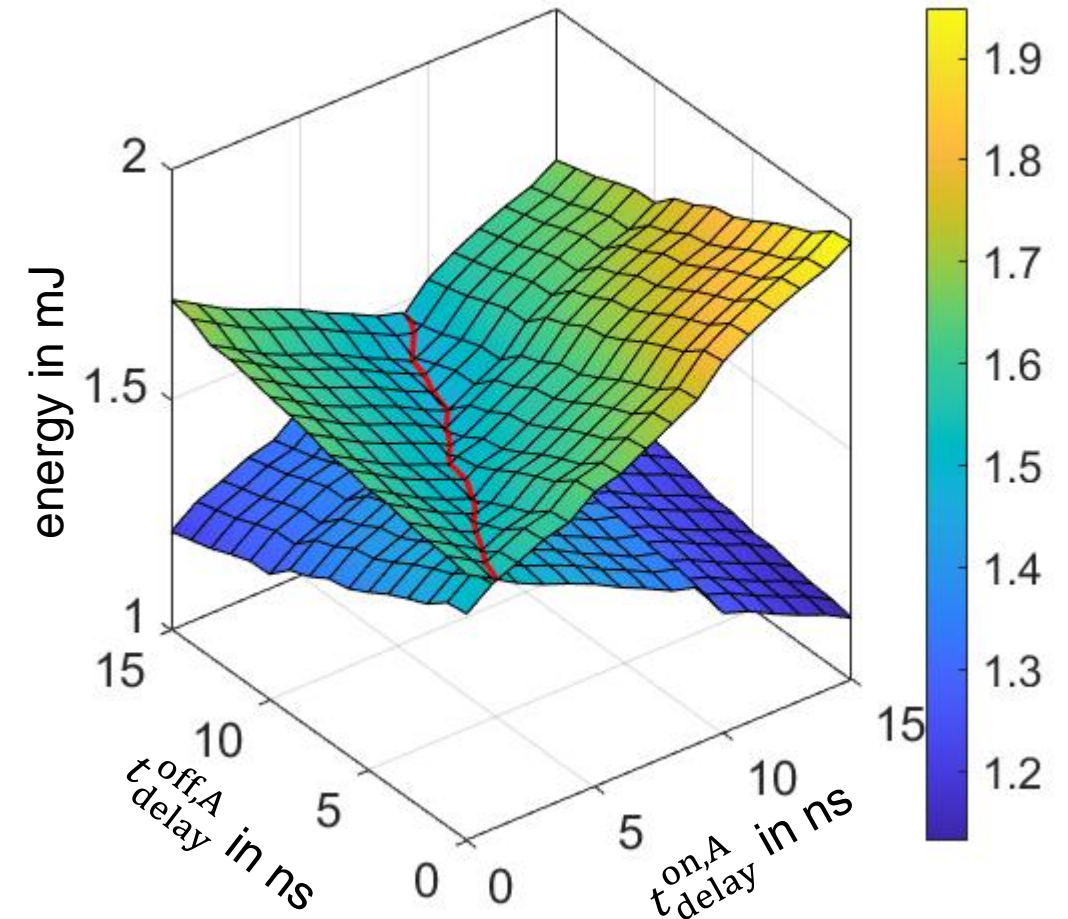


Influence of Gate Delay on Current Transients Turn-off



Conclusions & Outlook

- Proposed driver can freely shift the switching losses between parallel MOSFETs
- Highly beneficial for MOSFETs with different thermal resistance with regard to the cooling system
- Equal aging of the MOSFETs can be achieved
- Influence of temperature and different operating points needs to be examined
- Supported by the German Federal Ministry of Education and Research as part of the project SiCnifikant (16EMO0304)





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